

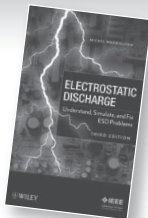
Discover these Essential New Titles from Wiley and Wiley-IEEE Press

Electro Static Discharge: Understand, Simulate, and Fix ESD Problems, 3rd Edition

Michel Mardiguian

9780470397046 • Cloth • 299pp • \$99.95
Wiley-IEEE Press • September 2009

Recognizing its methodic, step-by-step attack of the electrostatic discharge (ESD) problem, the initial release of this book was quoted by specialists as "the most thorough and concise treatment of the broad ESD continuum that is available." This Third Edition delivers the same trusted coverage of the topic while also incorporating recent technological advances that have taken place in the engineering community.



Mobile Communication Systems and Security

Man Young Rhee

9780470823361 • Cloth • 448pp • \$140.00
Wiley-IEEE Press • April 2009

This book arms readers with a thorough understanding of all major cellular air-interface technologies and their security layer techniques. Rhee covers the technological development of wireless mobile communications in compliance with each iterative generation up to 3G systems and beyond, with an emphasis on wireless security aspects. By progressing in a systematic manner, presenting the theory and practice of wireless mobile technologies along with various security problems, readers will gain an intimate sense of how mobile systems operate and how to address complex security issues.

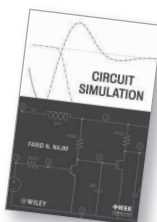


Circuit Simulation

Farid N. Najm

9780470538715 • Cloth • 344pp • \$115.00
Wiley-IEEE Press • January 2010

A definitive text on developing circuit simulators *Circuit Simulation* gives a clear description of the numerical techniques and algorithms that are part of modern circuit simulators, with a focus on the most commonly used simulation modes: DC analysis and transient analysis. Tested in a graduate course on circuit simulation at the University of Toronto, this unique text provides the reader with sufficient detail and mathematical rigor to write his/her own basic circuit simulator.

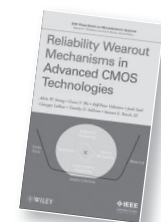


Reliability Wearout Mechanisms in Advanced CMOS Technologies

Alvin W. Strong, Ernest Y. Wu, Rolf-Peter Vollertsen, Jordi Sune, Giuseppe La Rosa, Timothy D. Sullivan, and Stewart E. Rauch III

9780471731726 • Cloth • 624pp • \$140.00
Wiley-IEEE Press • August 2009

A comprehensive treatment of all aspects of CMOS reliability wearout mechanisms. This book covers everything students and professionals need to know about CMOS reliability wearout mechanisms, from basic concepts to the tools necessary to conduct reliability tests and analyze the results. It is the first book of its kind to bring together the pertinent physics, equations, and procedures for CMOS technology reliability in one place.



Compact MOSFET Models for VLSI Design

A. B. Bhattacharyya

9780470823422 • Cloth • 512pp • \$125.00
Wiley-IEEE Press • April 2009

Practicing designers, students, and educators in the semiconductor field face an ever expanding portfolio of MOSFET models. In *Compact MOSFET Models for VLSI Design*, A.B. Bhattacharyya presents a unified perspective on the topic, allowing the practitioner to view and interpret device phenomena concurrently using different modeling strategies. Readers will learn to link device physics with model parameters, helping to close the gap between device understanding and its use for optimal circuit performance.

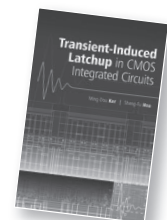


Transient-Induced Latchup in CMOS Integrated Circuits

Ming-Dou Ker and Sheng-Fu Hsu

9780470824078 • Cloth • 320pp • \$140.00
Wiley-IEEE Press • September 2009

This is the book all semiconductor device engineers must read to gain a practical feel for latchup-induced failure to produce lower-cost and higher-density chips. *Transient-Induced Latchup in CMOS Integrated Circuits* equips the practicing engineer with all the tools needed to address this regularly occurring problem while becoming more proficient at IC layout. Ker and Hsu introduce the phenomenon and basic physical mechanism of latchup, explaining the critical issues that have resurfaced for CMOS technologies.



Grounds for Grounding : A Circuit to System Handbook

Elya B. Joffe, Kai-Sang Lock

9780471660088 • Cloth • 1064pp • \$145.00
Wiley-IEEE Press • December 2009

The first book to cover grounding from the circuit to system and across the entire spectrum of applications *Grounds for Grounding* provides a complete and thorough approach to the subject of designing electrical and electronic circuits and systems, blending theory and practice to demonstrate how a few basic rules can be applied across a broad range of applications.

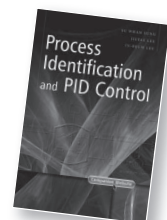


Process Identification and PID Control

Su Whan Sung, Jietae Lee, and In-Beum Lee

9780470824108 • Cloth • 352pp • \$140.50
Wiley-IEEE Press • June 2009

Process Identification and PID Control enables students and researchers to understand the basic concepts of feedback control, process identification, autotuning as well as design and implement feedback controllers, especially PID controllers.



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